



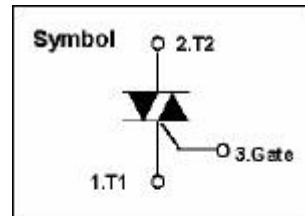
Shantou Huashan Electronic Devices Co.,Ltd.

**HTN4A60S**

## NON INSULATED TYPE SENSITIVE GATE TRIAC (T0-126 PACKAGE)

### Features

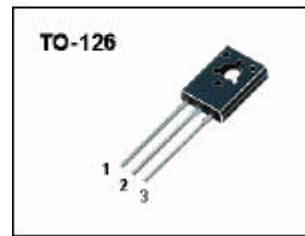
- \* Repetitive Peak Off-State Voltage: 600V
- \* R.M.S On-state Current( $I_{T(RMS)}=4A$ )
- \* High Commutation dv/dt
- \* Sensitive Gate Triggering 4 Mode



### General Description

The device is sensitive gate triac suitable for direct coupling to TTL,HTL,CMOS and application such as various logic functions, low power AC switching applications, such as fan speed, small light controllers and home appliance equipment.

### Absolute Maximum Ratings ( $T_a=25^\circ C$ )



$T_{stg}$ ——Storage Temperature .....	-40~125
$T_j$ ——Operating Junction Temperature .....	-40~125
$P_{GM}$ ——Peak Gate Power Dissipation .....	1.5W
$P_G(AV)$ ——Average Gate Power Dissipation .....	0.1W
$V_{DRM}$ ——Repetitive Peak Off-State Voltage .....	600V
$I_T(RMS)$ ——R.M.S On-State Current( $T_a=95^\circ C$ ).....	4.0A
$V_{GM}$ ——Peak Gate Voltage .....	7.0V
$I_{GM}$ ——Peak Gate Current .....	1.0A
$I_{TSM}$ ——Surge On-State Current (One Cycle, 50/60Hz,Peak,Non-Repetitive) .....	30/33A



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**HTN4A60S****Electrical Characteristics ( T<sub>a</sub>=25 °C )**

Symbol	Items	Min.	Typ.	Max.	Unit	Conditions
I <sub>DRM</sub>	Repetitive Peak Off-State Current			1.0	mA	V <sub>D</sub> =V <sub>DRM</sub> , Single Phase, Half Wave, T <sub>J</sub> =125
V <sub>TM</sub>	Peak On-State Voltage			1.7	V	I <sub>T</sub> =6A, Inst. Measurement
I <sub>+GT1</sub>	Gate Trigger Current ( + )			5.0	mA	V <sub>D</sub> =6V, R <sub>L</sub> =10 ohm
I <sub>-GT1</sub>	Gate Trigger Current ( - )			5.0	mA	V <sub>D</sub> =6V, R <sub>L</sub> =10 ohm
I <sub>-GT3</sub>	Gate Trigger Current ( - )			5.0	mA	V <sub>D</sub> =6V, R <sub>L</sub> =10 ohm
I <sub>+GT3</sub>	Gate Trigger Current ( + )			10.0	mA	V <sub>D</sub> =6V, R <sub>L</sub> =10 ohm
V <sub>+GT1</sub>	Gate Trigger Voltage ( + )			1.4	V	V <sub>D</sub> =6V, R <sub>L</sub> =10 ohm
V <sub>-GT1</sub>	Gate Trigger Voltage ( - )			1.4	V	V <sub>D</sub> =6V, R <sub>L</sub> =10 ohm
V <sub>-GT3</sub>	Gate Trigger Voltage ( - )			1.4	V	V <sub>D</sub> =6V, R <sub>L</sub> =10 ohm
V <sub>+GT3</sub>	Gate Trigger Voltage ( + )			1.8	V	V <sub>D</sub> =6V, R <sub>L</sub> =10 ohm
V <sub>GD</sub>	Non-Trigger Gate Voltage	0.2			V	T <sub>J</sub> =125 °C, V <sub>D</sub> =1/2V <sub>DRM</sub>
(dv/dt) <sub>c</sub>	Critical Rate of Rise of Off-State Voltage at Commutation	11			V/ $\mu$ S	T <sub>J</sub> =125 °C, V <sub>D</sub> =2/3V <sub>DRM</sub> (di/dt) <sub>c</sub> = -2.0A/ms
I <sub>H</sub>	Holding Current			10	mA	
R <sub>th(j-c)</sub>	Thermal Resistance			3.5	/W	Junction to case

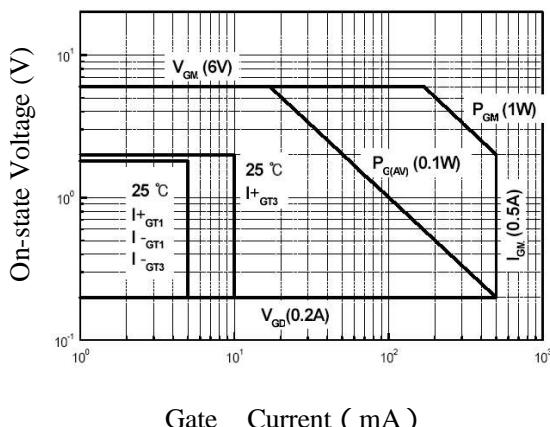


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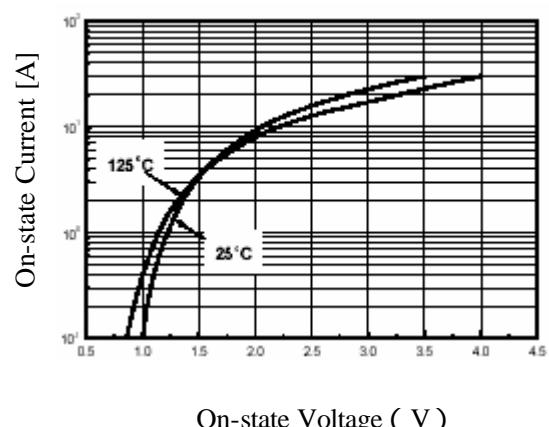
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## Performance Curves

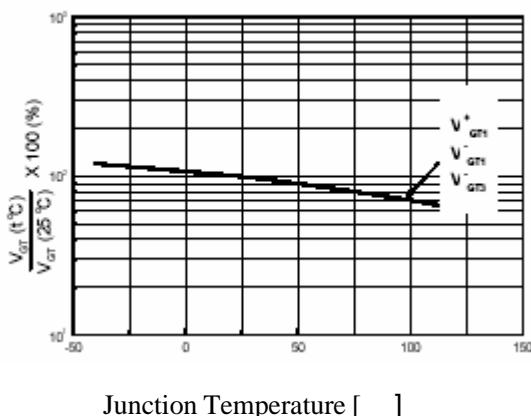
**Fig 1. Gate Characteristics**



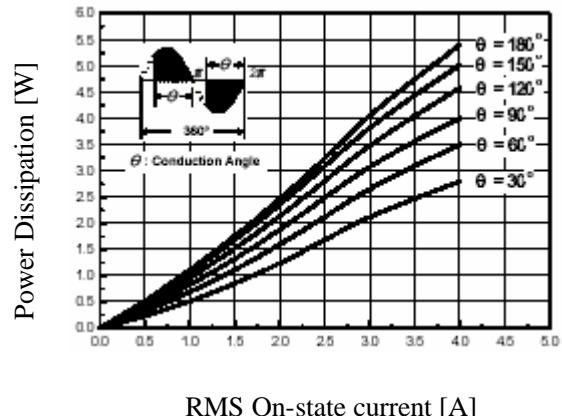
**Fig 2. On-State Voltage**



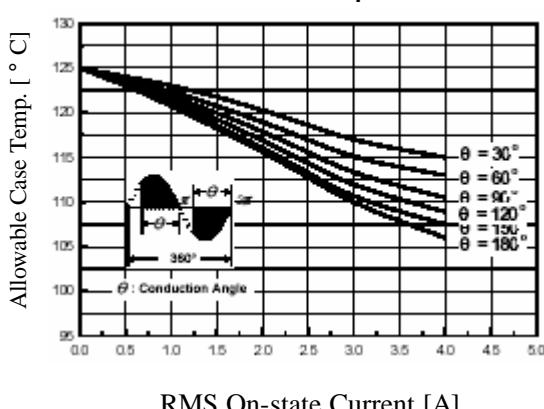
**Fig 3. Gate Trigger Voltage vs. Junction Temperature**



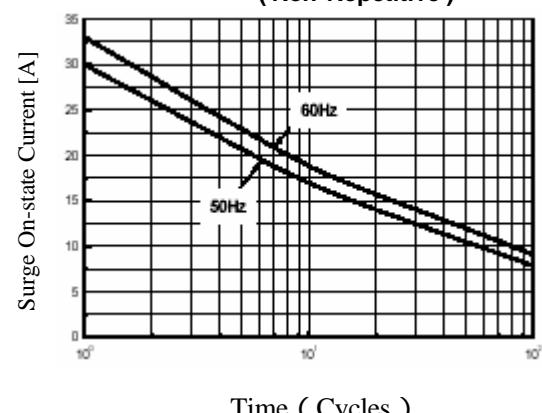
**Fig 4. On State Current vs. Maximum Power Dissipation**



**Fig 5. On State Current vs. Allowable Case Temperature**



**Fig 6. Surge On-State Current Rating (Non-Repetitive)**

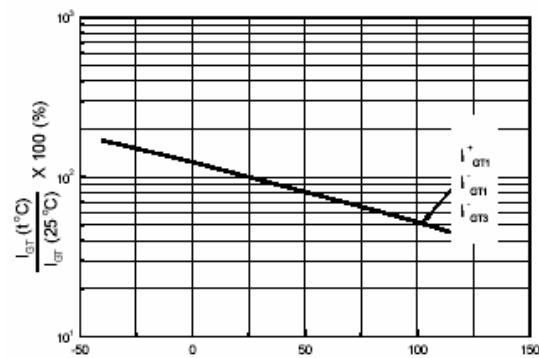




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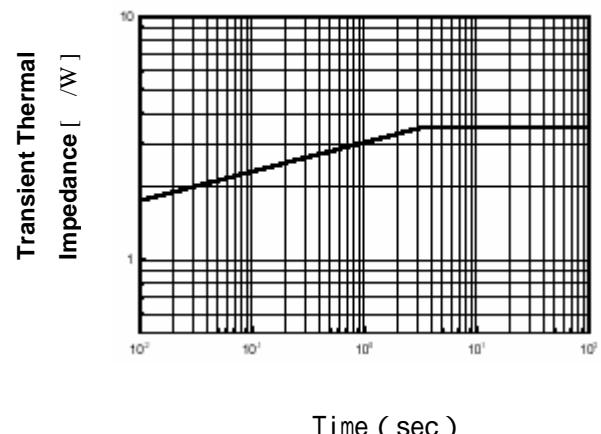
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**Fig 7. Gate Trigger Current vs.  
Junction Temperature**



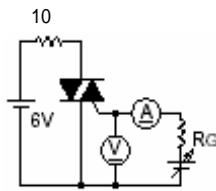
Junction Temperature [ ]

**Fig 8. Transient Thermal Impedance**

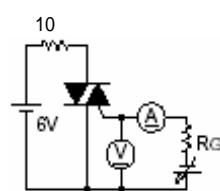


Time ( sec )

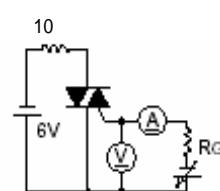
**Fig 9. Gate Trigger Characteristics Test Circuit**



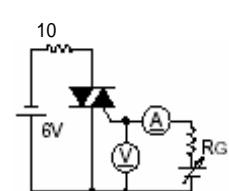
Test Procedure



Test Procedure



Test Procedure



Test Procedure